

**Notice of References Cited**

Application/Control No.

10/081,665

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

Ram N Kackar

Art Unit

1763

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,150,638	11-2000	Strodtbeck et al.	219/502
	B	US-6,592,673	07-2003	Welch et al.	118/676
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05129421 A	05-1993	Japan	MATSUNAGA, DAISUKE	H01L 21/68
	O	JP 11214484 A	08-1999	Japan	KUMAZAKI, KIYOAKI	H01L 21/68
	P	JP 11069855 A	03-1999	Japan	MABUCHI et al.	H02N 13/00
	Q	JP 10160420 A	06-1998	Japan	SHU et al.	G01B 11/06
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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